

Enhanced M π log Models for Power Integrity Analysis.

Modeling from simulation and measurement,
IBIS data extraction, crossvalidation

A. Girardi¹, I.S. Stievano², R. Izzi¹, T. Lessio¹, F.G. Canavero², I. Maio², L. Rigazio²

¹ Numonyx Italy S.r.l., ² Politecnico di Torino, Italy

Ref. contacts: {antonio.girardi@numonyx.com, igor.stievano@polito.it}



MOCHA, MOdelling and CHAracterization for SiP - Signal and Power Integrity Analysis

(www.mocha.polito.it)

❑ European Project FP7-ICT-2007-1* (Jan 2008 – Mar 2010)

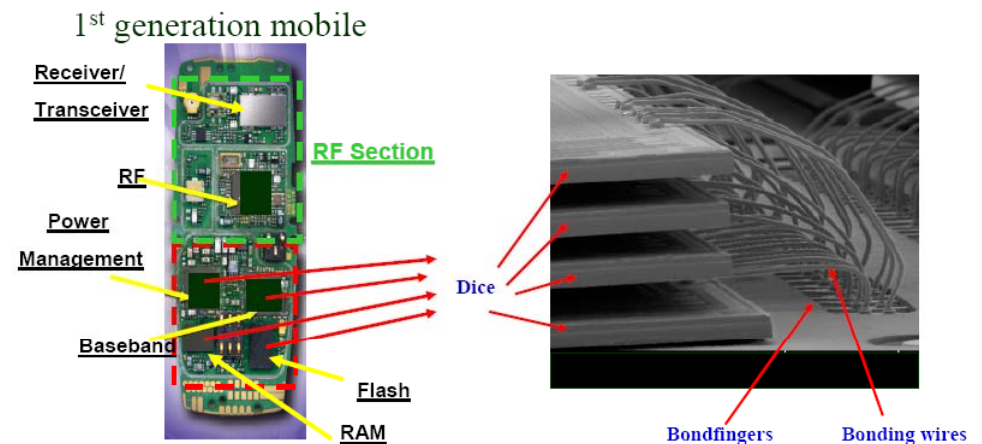
“Develop reliable modelling and simulation solutions for SiP design verification”

❑ Participants:

- **Numonyx Italy Srl (Italy) [Coordinator]**
- Politecnico di Torino (Italy)
- Cadence Design Systems GmbH (Germany)
- Agilent Technologies (Belgium)
- Universidade de Aveiro (Portugal),
- Microwave Characterization Center (France)

❑ Work Packages

- WP1, IC power integrity model
- **WP2, IC buffers' innovative modelling approach**
- WP3, SiP design and verification EDA platform
- WP4, SiP signal integrity measurement platform



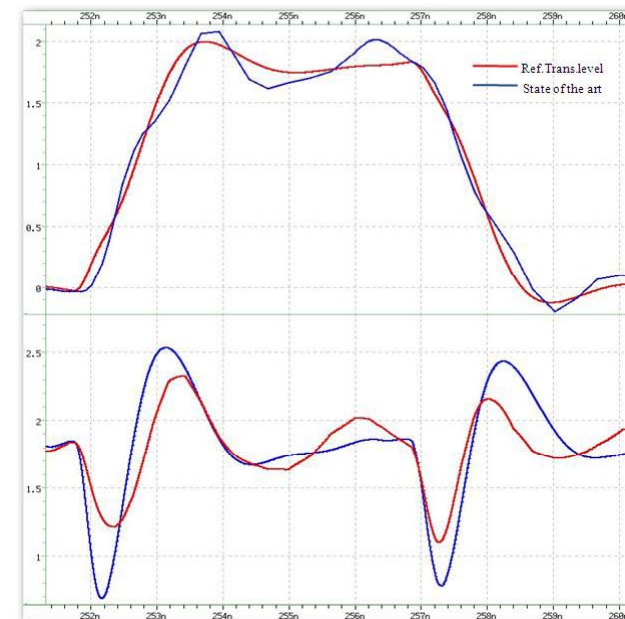
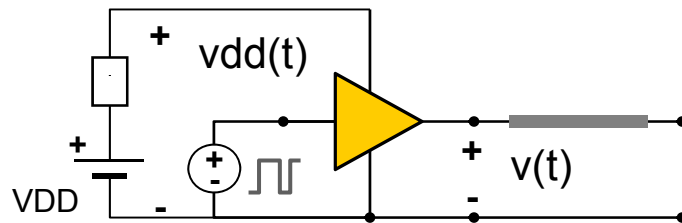
* The research leading to these results has received funding from the European Community's Seventh Framework Programme FP7-ICT-2007-1 under the MOCHA (MOdeling and CHAracterization for SiP - Signal and Power Integrity Analysis) grant n. 216732.

WP2 overview

Objective: Development of **accurate** and **efficient** models of digital ICs

❑ Overcome current limitations of existing models

e.g., state-of-the art models allow only for limited power supply variations



— Ref. trans. level — State-of-the art

❑ Generate models from **measurements** & **simulations**

WP2 achievements (i)

TASK 2.1

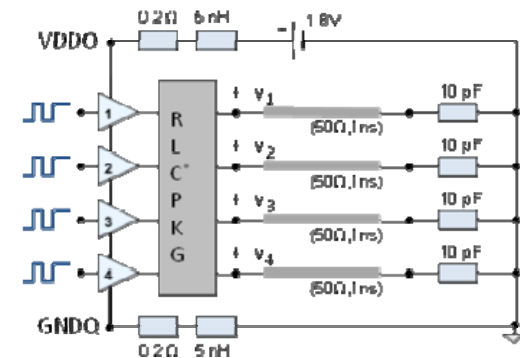
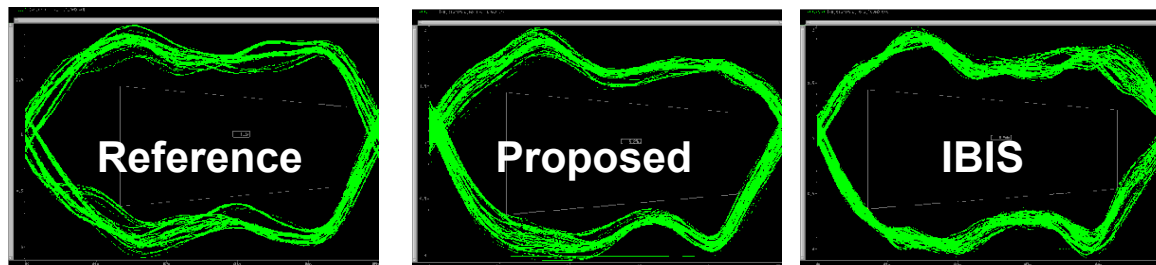
- ❑ Availability of the **General structure** of the **extended model** for digital buffers
- ❑ Procedure for **parameter estimation** from **simulation / measurement**
- ❑ Model **implementation** in different formats (HSPICE, ELDO, VERILOG-A,...)

TASK 2.2

- ❑ Application to **test cases** (proprietary and third party devices) **from simulation**

WP2 achievements (ii)

□ Model Accuracy, second test case (estimation from simulation)



	Eye opening	Error	CPU
Reference (trans. level)	72%	-	773 s
IBIS	78.8 %	9.5 %	13 s (59x)
Proposed (M π LOG)	73.8 %	2.5 %	31 s (25x)

✓ Improved Accuracy

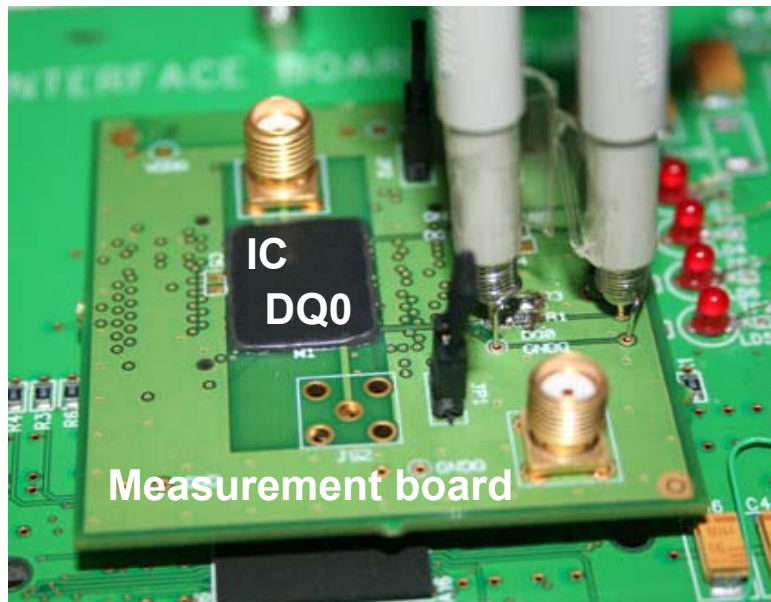
✓ High efficiency

WP2 achievements (iii)

TASK 2.3

- Design two **test boards** for the characterization of the IC ports of the MOCHA test cases

e.g., first test case, DQ0 I/O buffer



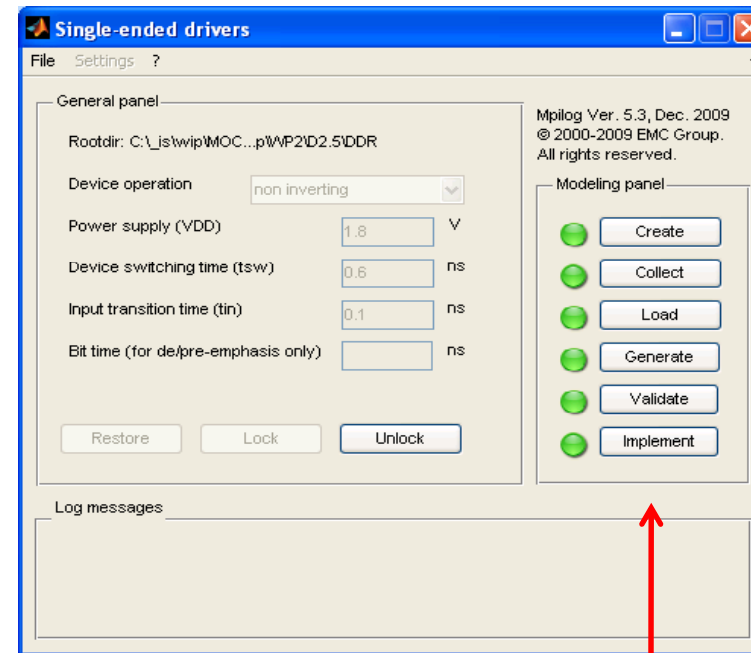
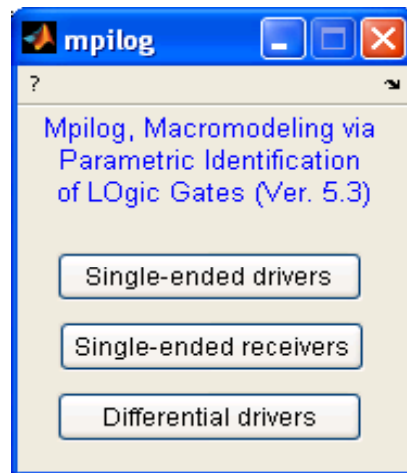
Device models
from transient
port voltage and
current
responses
recorded during
IC normal
operation

WP2 achievements (iv)

TASK 2.4

❑ Tool for the interactive generation of IC models

→ **Mπlog ver. 5.3**,
available @
www.emc.polito.it

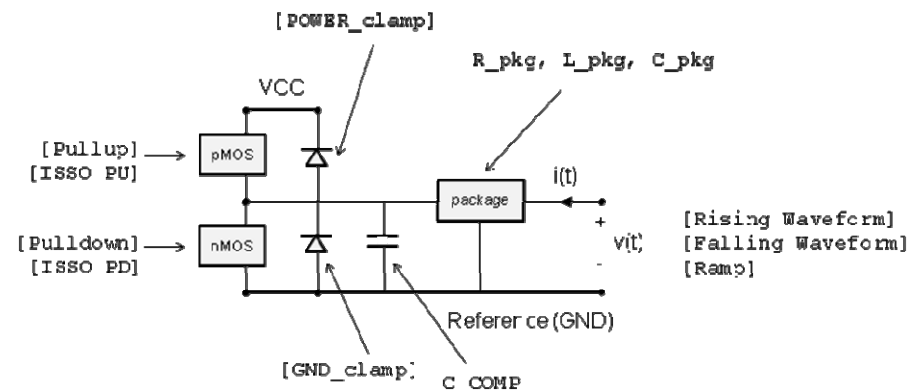
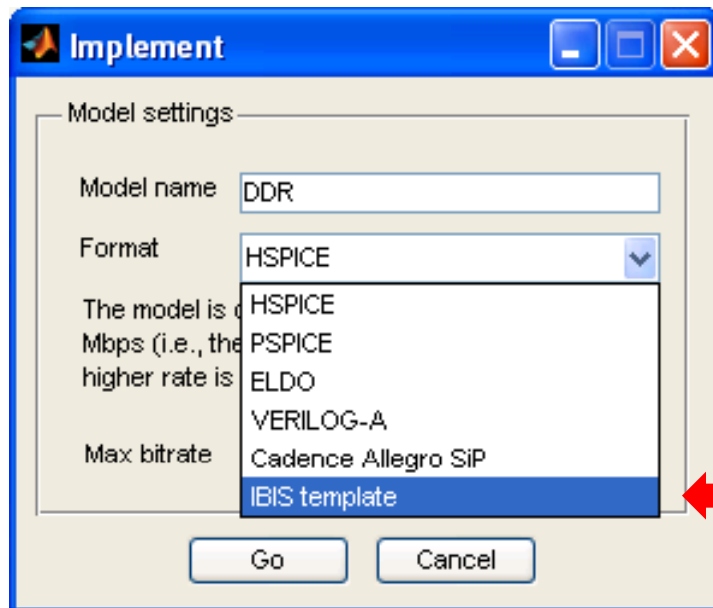


Guided step-by-step modeling procedure

WP2 achievements (v)

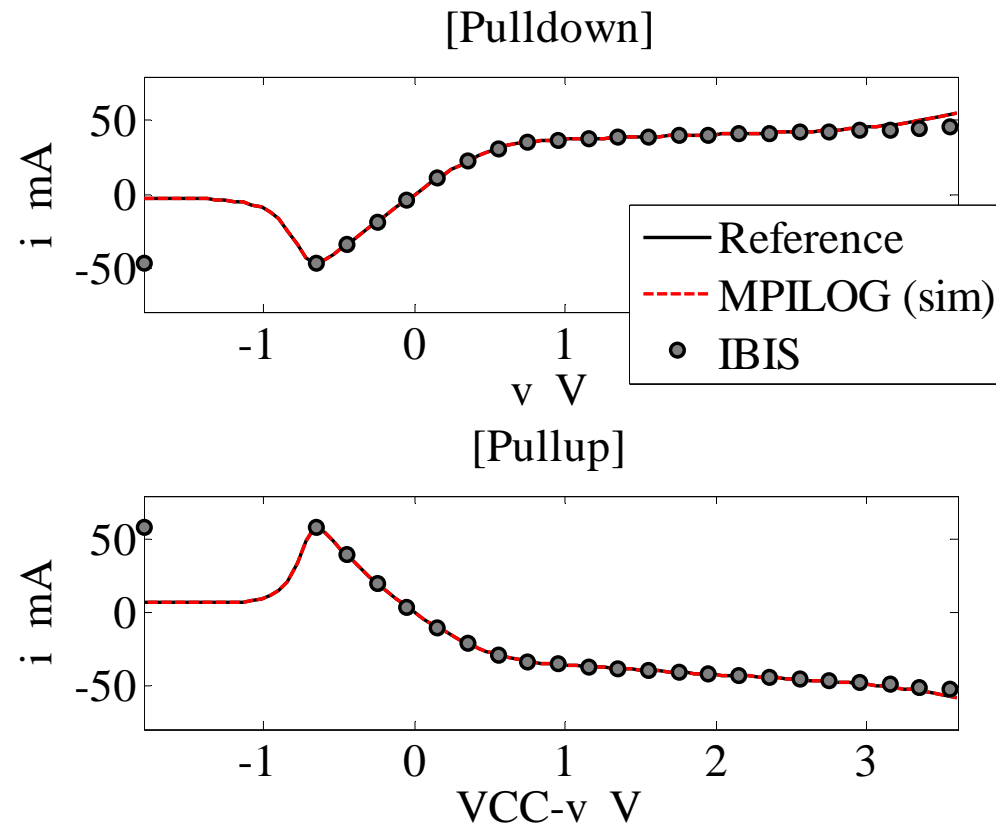
TASK 2.5

- procedure for the **extraction** of device characteristics suggested by **IBIS** from the estimated models

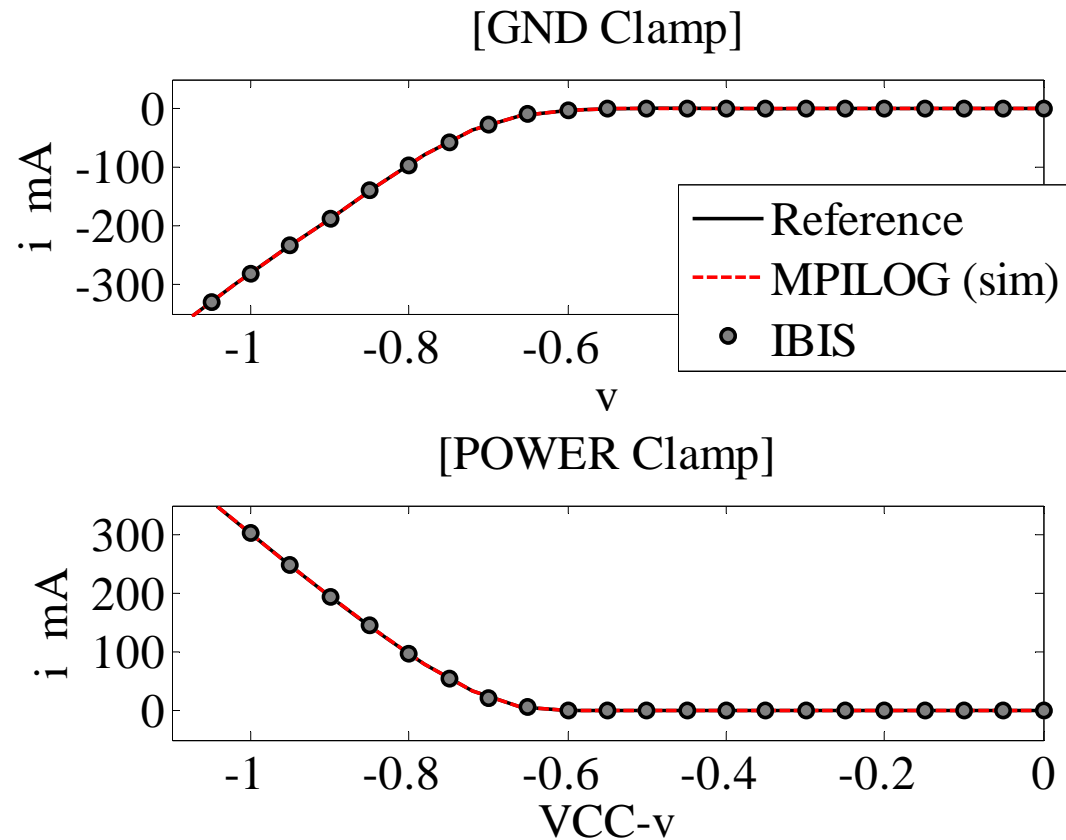


	IBIS	MPLOG (sim)
C_COMP	3.1pF	3.045 pF

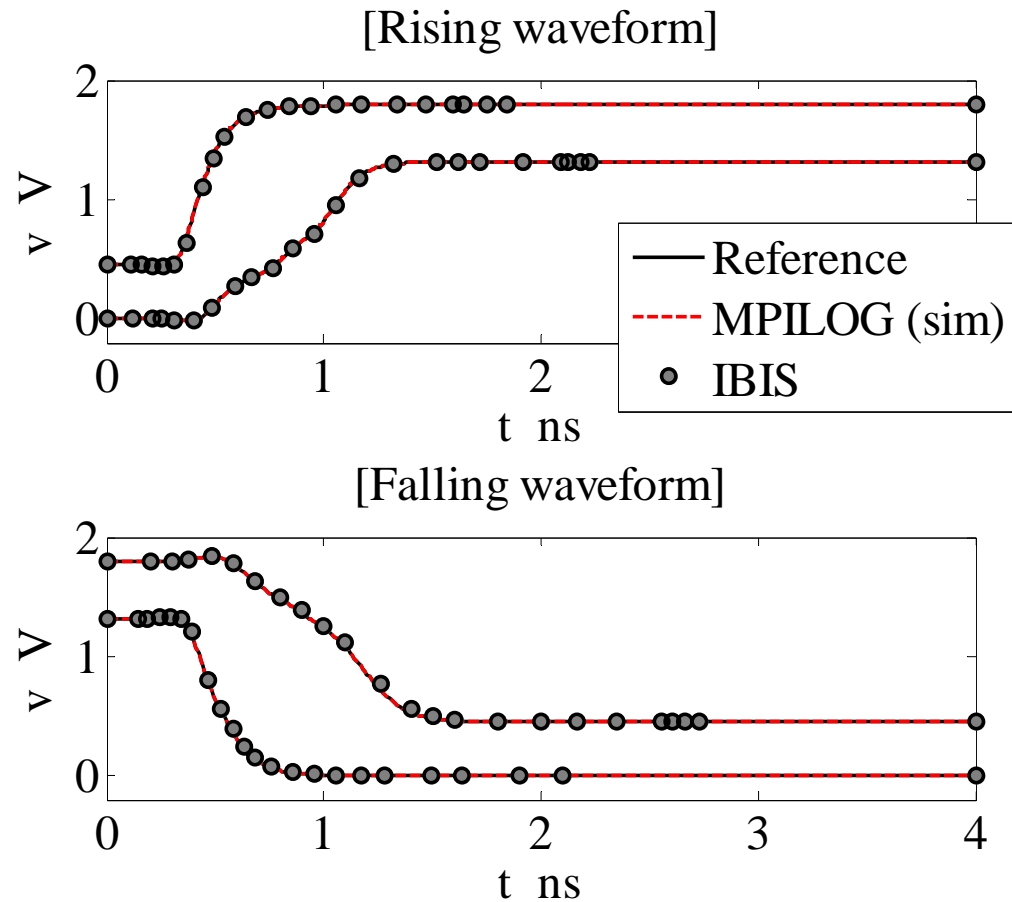
X-validation (ii)



X-validation (iii)

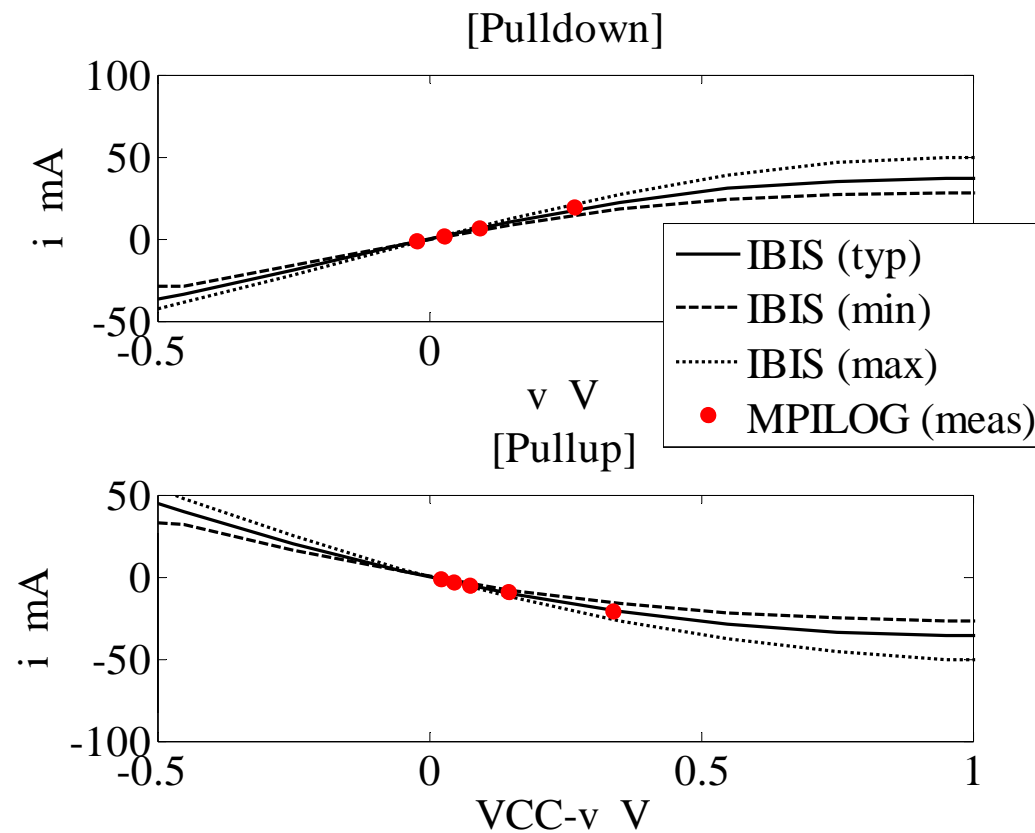


X-validation (iv)



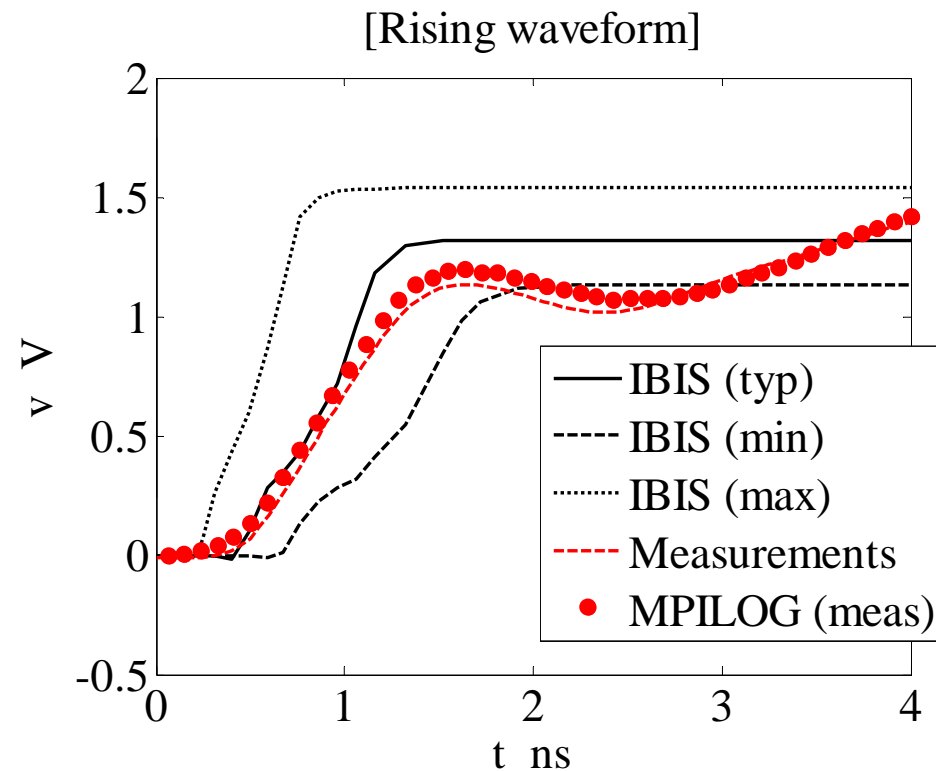
X-validation (v)

...model from real measured data



X-validation (vi)

...model from real measured data



$R_{\text{fixture}} = 47 \, \Omega$
 $L_{\text{fixture}} = 18 \, \text{nH}$
 $C_{\text{fixture}} = 7.4 \, \text{pF}$
 $V_{\text{fixture}} = 0\text{V}$

Q&A

